

**Notice of References Cited**

Application/Control No.

10/019,390

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

1745

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,338,622	08-1994	Hsu et al.	429/26
	B	US-			
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	E	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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